Welcome Message
from the General Co-Chairs
and Program Co-Chairs

Welcome to the 2004 IEEE International On-Line Testing Symposium! This year marks the 10th in a series of very productive technical meetings started in Nice, France, in 1995. The On-Line Testing Workshop has been created at a time when a variety of applications of electronic systems was growing rapidly and system complexity was seeing a formidable increase, thus the need for increased protection against field failures. Since then, new nanometric technologies have still increased the likelihood of faults, while many applications rely on integrated circuits to achieve safety, availability or security requirements. The design of modern electronics systems therefore needs efficient solutions combining high fault detection or tolerance with low cost and reduced time to market. The elevation of the workshop to a symposium in 2003 reflected both this trend and the recognition of this event as a major forum for sharing ideas and experiences with those working in this field.

The submissions came this year from 20 countries all over the world. We would like to thank all the members of the Program Committee for their hard work in selecting the 34 papers and 9 posters that appear in this year’s proceedings. We would also like to thank our keynote speakers and panel organizers and we hope that the attendees will find this technical program very stimulating.

Following the tradition, the symposium will be held in a nice island, but this year in the Atlantic Ocean. The organizers did an excellent work in planning this event, and we are confident that a charming and relaxing environment will favor very interesting technical discussions.

Have a nice and fruitful IEEE International On-Line Testing Symposium 2004!

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